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Application/Control No.	Applicant(s)/Patent under Reexamination
09/620,772	KAHN ET AL.
Examiner	Art Unit
Ellen C. Tran	2134

	SEARCHED			
Class	Subclass	Date	Examiner	
380	239	1/12/2007	ECT	
726	6	1/12/2007	ECT	
380	241	1/12/2007	ECT	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	1/12/2007	ECT
All claims were reviewed for possible 101 rejections	1/12/2007	ECT
NPL - IEEE & GOOGLE	1/12/2007	ECT
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